Sea	earch Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/706,498	ALLEN ET AL.
Examiner	Art Unit
Anthony Weier	1761

	SEARCHED		
Class	Subclass	Date	Examiner
426	655, 429, 430, 495	11/10/2005	AW
			-

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	1		

SEAR((INCLUDING SE	CH NOTES EARCH STRATEGY	′)
	DATE	EXMR
Inventor Search	. 11/10/2005	AW